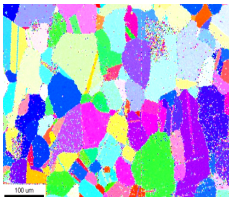
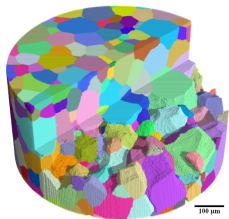


Reconstruction of TiAl microstructures by X-ray diffraction contrast tomography

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Industrial partner : Safran Tech Academic partner : ESRF



- Study of three TiAl microstructures (gamma, lamellar, duplex)
- X-ray diffraction contrast tomography of millimetric size specimens at ESRF
- 3D morphological and crystallographic mapping
- Input for future microstructure FEA